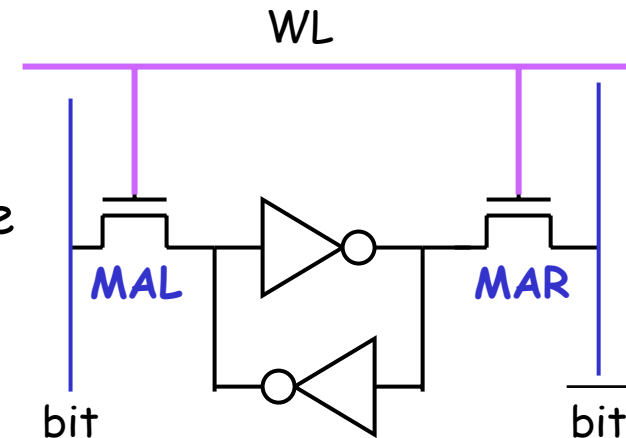


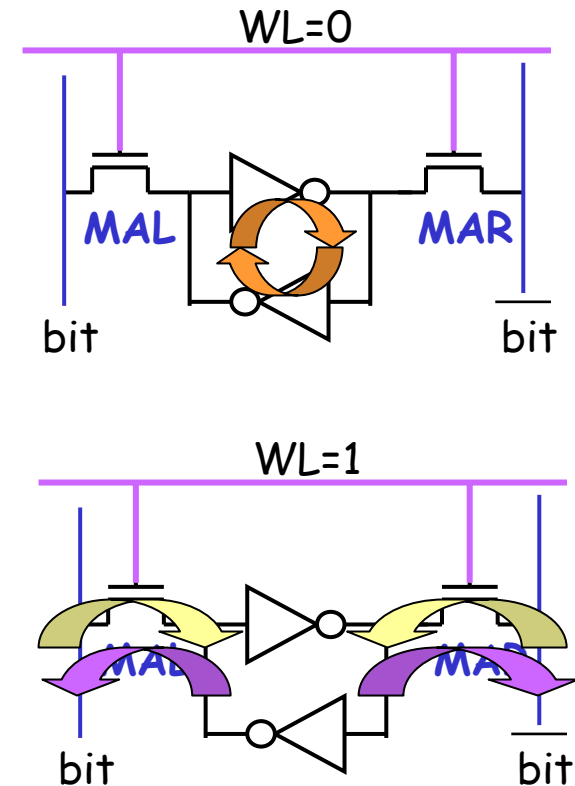
# SRAM Basics

- SRAM = Static Random Access Memory
  - Static: holds data as long as power is applied
  - Volatile: can not hold data if power is removed
- 3 Operation States
  - hold
  - write
  - read
- Basic 6T (6 transistor) SRAM Cell
  - bistable (cross-coupled) INVs for storage
  - access transistors MAL & MAR
    - access to stored data for read and write
  - word line, WL, controls access
    - WL = 0, hold operation
    - WL = 1, read or write operation



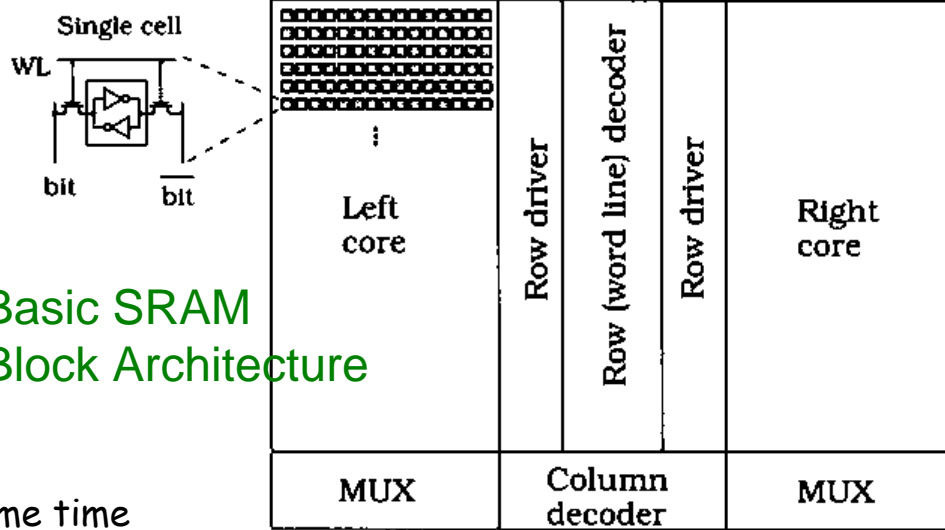
# SRAM Operations

- Hold
  - word line = 0, access transistors are OFF
  - data held in latch
- Write
  - word line = 1, access tx are ON
  - new data (voltage) applied to bit and bit\_bar
  - data in latch overwritten with new value
- Read
  - word line = 1, access tx are ON
  - bit and bit\_bar read by a sense amplifier
- Sense Amplifier
  - basically a simple differential amplifier
  - comparing the difference between bit and bit\_bar
    - if bit > bit\_bar, output is 1
    - if bit < bit\_bar, output is 0
    - allows output to be set quickly without fully charging/discharging bit line



# SRAM Block Architecture

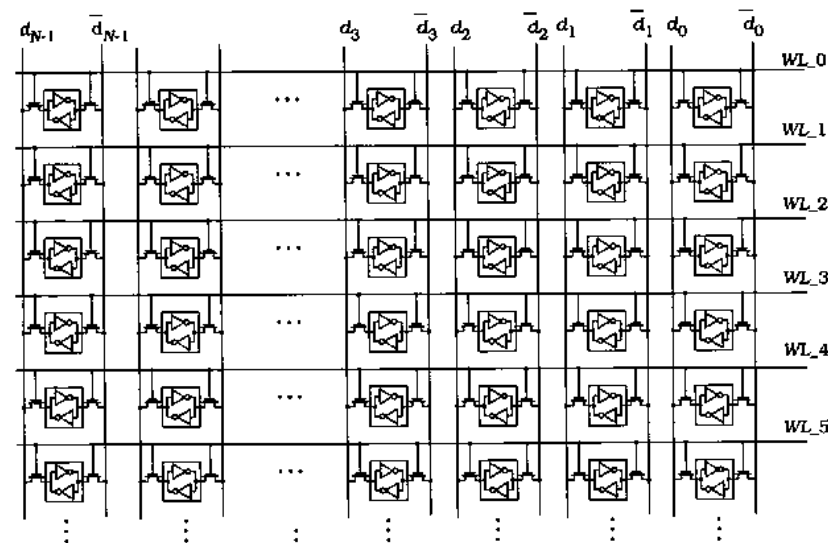
- Example: 2-Core design
  - core width =  $k \cdot n$ 
    - $n$  = SRAM word size; 8, 16, etc.
    - $k$  = multiplier factor, 2,3,4,etc.
  - shared word-line circuits
    - horizontal word lines
    - WL set by **row decoder**
      - placed in center of 2 cores
      - WL in both cores selected at same time



Basic SRAM Block Architecture

- Addressing Operation
  - address word determines which row is active (which WL = 1) via **row decoder**
  - row decoder outputs feed **row drivers**
    - buffers to drive large WL capacitance

- Physical Design
  - layout scheme matches regular patterning shown in schematic
    - horizontal and vertical routing



Expanded Core View



# DRAM Operation

- RAM data is held on the storage capacitor
  - temporary - due to leakage currents which drain charge

- Charge Storage

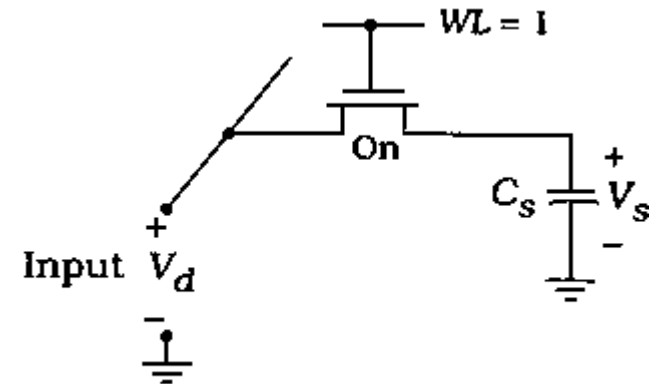
- if  $C_s$  is charged to  $V_s$
- $Q_s = C_s V_s$ 
  - if  $V_s = 0$ , then  $Q_s = 0$ : LOGIC 0
  - if  $V_s = \text{large}$ , then  $Q_s > 0$ : LOGIC 1

- Write Operation

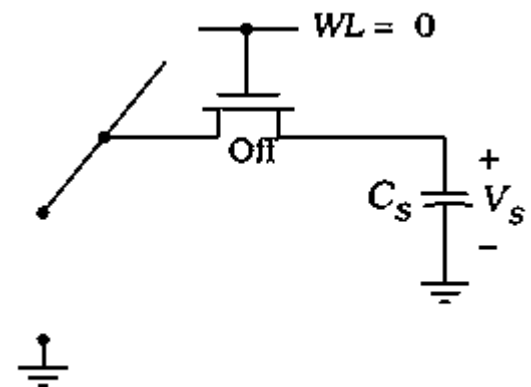
- turn on access transistor:  $WL = VDD$
- apply voltage,  $V_d$  (high or low), to bit line
- $C_s$  is charged (or discharged)
- if  $V_d = 0$ 
  - $V_s = 0$ ,  $Q_s = 0$ , store logic 0
- if  $V_d = VDD$ 
  - $V_s = VDD - V_{tn}$ ,  $Q_s = C_s(VDD - V_{tn})$ , logic 1

- Hold Operation

- turn off access transistor:  $WL = 0$ 
  - charge held on  $C_s$



(a) Write operation

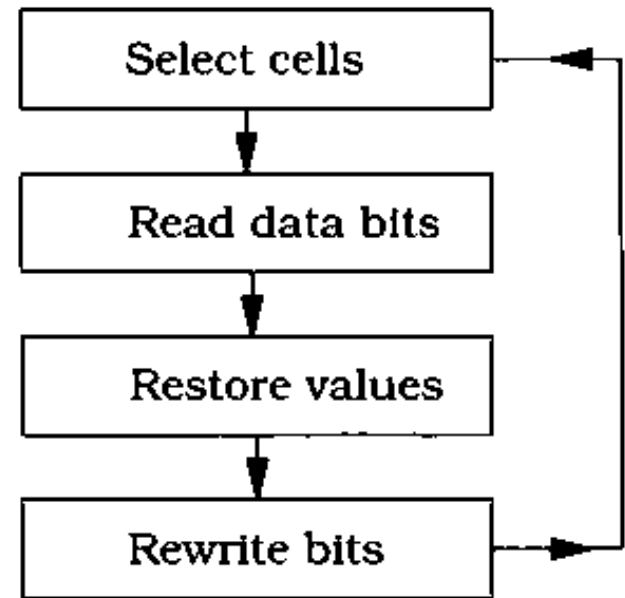


(b) Hold



# Refresh Rate

- DRAM is "Dynamic", data is stored for only short time
- Refresh Operation
  - to hold data as long as power is applied, data must be refreshed
  - periodically read every cell
    - amplify cell data
    - rewrite data to cell
- Refresh Rate,  $f_{\text{refresh}}$ 
  - frequency at which cells must be refreshed to maintain data
  - $f_{\text{refresh}} = 1 / 2t_h$
  - must include refresh circuitry in a DRAM circuit



Refresh operation



# DRAM Read Operation

- Read Operation

- turn on access transistor
- charge on  $C_s$  is redistributed on the bit line capacitance,  $C_{bit}$
- this will change the bit line voltage,  $V_{bit}$
- which is amplified to read a 1 or 0

- Charge Redistribution

- initial charge on  $C_s$ :  $Q_s = C_s V_s$
- redistributed on  $C_{bit}$  until
  - $V_{bit} = V_s = V_f$  (final voltage)
- $Q_s = C_s V_f + C_{bit} V_f$
- $C_s V_s = V_f (C_s + C_{bit})$ 
  - due to charge conservation
- $V_f = C_s V_s / (C_s + C_{bit})$ , which is always less than  $V_s$ 
  - $V_f$  typically very small and requires a good sense amplifier

